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- Controlled Baseline
  - One Assembly/Test Site, One Fabrication Site
- Extended Temperature Performance of -40°C to 125°C
- Enhanced Diminishing Manufacturing Sources (DMS) Support
- Enhanced Product Change Notification
- Qualification Pedigree<sup>†</sup>
- Buffered Inputs
- Common 3-State Output-Enable Control
- 3-State Outputs
- Bus-Line Driving Capability
- Typical Propagation Delay (Clock to Q):
   15 ns at V<sub>CC</sub> = 5 V, C<sub>L</sub> = 15 pF, T<sub>Δ</sub> = 25°C
- Fanout (Over Temperature Range)
  - Standard Outputs ... 10 LSTTL Loads
  - Bus Driver Outputs ... 15 LSTTL Loads

- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- V<sub>CC</sub> Voltage = 4.5 V to 5.5 V
- Direct LSTTL Input Logic Compatibility,
   V<sub>IL</sub> = 0.8 V (Max), V<sub>IH</sub> = 2 V (Min)
- CMOS Input Compatibility,  $I_I \le 1 \mu A$  at  $V_{OL}$ ,  $V_{OH}$

#### M OR PW PACKAGE (TOP VIEW)

		${f T}$		1
OE [	1	$\cup$	20	] ∨ <sub>cc</sub>
D0 [	2		19	] Q0
D1 [	3		18	] Q1
D2 [	4		17	] Q2
D3 [	5		16	] Q3
D4 [	6		15	] Q4
D5 [	7		14	] Q5
D6 [	8		13	] Q6
D7 [	9		12	] Q7
GND [	10		11	] CP
				•

### description/ordering information

The CD74HCT574 is an octal D-type flip-flop with 3-state outputs and the capability to drive 15 LSTTL loads. The eight edge-triggered flip-flops enter data into their registers on the low-to-high transition of the clock (CP). The output enable  $(\overline{OE})$  controls the 3-state outputs and is independent of the register operation. When  $\overline{OE}$  is high, the outputs are in the high-impedance state.

### ORDERING INFORMATION

TA	PACK	AGE‡	ORDERABLE PART NUMBER	TOP-SIDE MARKING
4000 1- 40500	SOIC - M	Tape and reel	CD74HCT574QM96EP	HCT574EP
-40°C to 125°C	TSSOP - PW	Tape and reel	CD74HCT574QPWREP	HCT574EP

<sup>&</sup>lt;sup>‡</sup> Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



<sup>†</sup> Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.

# CD74HCT574-EP HIGH-SPEED CMOS LOGIC OCTAL D-TYPE FLIP-FLOP 3-STATE, POSITIVE-EDGE TRIGGERED SCLS571 - FEBRUARY 2004

#### **FUNCTION TABLE**

	OUTPUT		
OE	СР	D	Q
L	<b>↑</b>	Н	Н
L	<b>↑</b>	L	L
L	L	Χ	Q <sub>0</sub>
Н	Х	Х	Z

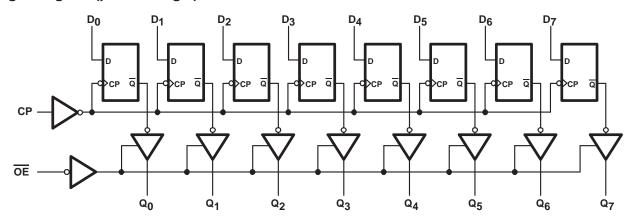
NOTE: H = High voltage level (steady state) L = Low voltage level (steady state)

X = Don't care

 $\uparrow$  = Transition from low to high level  $Q_0$  = Level before the indicated steady-state conditions were established

Z = High-impedance state

# logic diagram (positive logic)



# CD74HCT574-EP HIGH-SPEED CMOS LOGIC OCTAL D-TYPE FLIP-FLOP 3-STATE, POSITIVE-EDGE TRIGGERED

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## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub> (see Note 1)	0.5 V to 7 V
Input clamp current, $I_{IK}$ ( $V_I < -0.5 \text{ V or } V_I > V_{CC} + 0.5 \text{ V}$ )	±20 mA
Output clamp current, $I_{OK}$ ( $V_O < -0.5 \text{ V or } V_O > V_{CC} + 0.5 \text{ V}$ )	
Drain current per output, $I_O$ ( $V_O > -0.5 \text{ V}$ or $V_O < V_{CC} + 0.5 \text{ V}$ )	±35 mA
Output source or sink current per output, $I_O$ ( $V_O > -0.5$ V or $V_O < V_{CC} + 0.5$ V)	±25 mA
Continuous current through V <sub>CC</sub> or GND, I <sub>CC</sub>	±50 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 2): M package	58°C/W
PW package	69°C/W
Maximum junction temperature, T <sub>J</sub>	150°C
Lead temperature (during soldering):	
At distance 1/16 $\pm$ 1/32 inch (1,59 $\pm$ 0,79 mm) from case for 10 s max	300°C
Storage temperature range, T <sub>stg</sub>	$-65^{\circ}\text{C}$ to $150^{\circ}\text{C}$

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltages referenced to GND unless otherwise specified.

2. The package thermal impedance is calculated in accordance with JESD 51-7.

## recommended operating conditions (see Note 3)

		М	IN	MAX	UNIT
Vcc	Supply voltage	4	.5	5.5	V
VIH	High-level input voltage $V_{CC} = 4.5 \text{ V}$ to	5.5 V	2		V
VIL	Low-level input voltage $V_{CC} = 4.5 \text{ V}$ to	5.5 V		0.8	V
VI	Input voltage		0	VCC	V
VO	Output voltage		0	VCC	V
	V <sub>CC</sub> = 2 V		0	1000	
t <sub>t</sub>	Input transition (rise and fall) time $V_{CC} = 4.5 \text{ V}$		0	500	ns
	V <sub>CC</sub> = 6 V				
TA	Operating free-air temperature		40	125	°C

NOTE 3: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



# CD74HCT574-EP HIGH-SPEED CMOS LOGIC OCTAL D-TYPE FLIP-FLOP 3-STATE, POSITIVE-EDGE TRIGGERED SCLS571 - FEBRUARY 2004

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		I <sub>O</sub> (mA)	v <sub>cc</sub>	T <sub>A</sub> = 25°C			T <sub>A</sub> = -	UNIT	
					MIN	TYP	MAX	MIN	MAX	
V	V V 22V	CMOS loads	-0.02	4.5 V	4.4			4.4		V
VOH	$V_I = V_{IH}$ or $V_{IL}$	TTL loads	-6	4.5 V	3.98			3.7		V
.,,	V VV	CMOS loads	0.02	4.5 V			0.1		0.1	.,
V <sub>OL</sub>	$V_I = V_{IH} \text{ or } V_{IL}$	TTL loads	6	4.5 V			0.26		0.4	V
lį	$V_I = V_{CC}$ or GND		0	5.5 V			±0.1		±1	μΑ
loz	$V_I = V_{IL} \text{ or } V_{IH},$	$V_O = V_{CC}$ or GND		6 V			±0.5		±10	μΑ
lcc	$V_I = V_{CC}$ or GND		0	5.5 V			8		160	μΑ
ΔlCC	$V_{I} = V_{CC} - 2.1 V,$	See Note 4		4.5 V to 5.5 V		100	360		490	μΑ
C <sub>IN</sub>	C <sub>L</sub> = 50 pF						10		10	pF
COUT	3-state						20		20	pF

NOTE 4: For dual-supply systems, theoretical worst-case (V<sub>I</sub> = 2.4 V, V<sub>CC</sub> = 5.5 V) specification is 1.8 mA.

## **HCT** input loading

TYPE	INPUT	UNIT LOADS†
	D0-D7	0.4
'574	СР	0.75
	ŌĒ	0.6

 $<sup>^{\</sup>dagger}$ Unit load is  $\Delta I_{CC}$  limit specified in electrical characteristics table, e.g., 360  $\mu A$  max at 25°C.

### timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

	PARAMETER	v <sub>cc</sub>	T <sub>A</sub> = 2	25°C	T <sub>A</sub> = -	UNIT	
			MIN	MAX	MIN	MAX	
fmax	Maximum clock frequency	4.5 V	30		20		MHz
t <sub>W</sub>	Clock pulse duration	4.5 V	16		24		ns
t <sub>su</sub>	Setup time, data before clock↑	4.5 V	12		18		ns
th	Hold time, data after clock↑	4.5 V	5		5		ns

# CD74HCT574-EP HIGH-SPEED CMOS LOGIC OCTAL D-TYPE FLIP-FLOP 3-STATE, POSITIVE-EDGE TRIGGERED

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## switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO	LOAD	ν <sub>CC</sub>	T	λ = 25°C	;	T <sub>A</sub> = -		UNIT
	(INPUT)	(OUTPUT)	CAPACITANCE		MIN	TYP	MAX	MIN	MAX	
	CD.	_	C <sub>L</sub> = 50 pF	4.5 V			33		50	
<sup>t</sup> pd	СР	Q	C <sub>L</sub> = 15 pF	5 V		15				ns
<b>A</b>	ŌĒ	_	C <sub>L</sub> = 50 pF	4.5 V			28		42	
<sup>t</sup> dis	OE	Q	C <sub>L</sub> = 15 pF	5 V		11				ns
	t <sub>en</sub> OE		$C_{L} = 50 \text{ pF}$	4.5 V			30		45	
<sup>t</sup> en	OE	Q	C <sub>L</sub> = 15 pF	5 V		12				ns
t <sub>t</sub>		Q	C <sub>L</sub> = 50 pF	4.5 V			12		18	ns
f <sub>max</sub>	СР		C <sub>L</sub> = 15 pF	5 V		60		·		MHz

## operating characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$ , input $t_r$ , $t_f = 6 \text{ ns}$

	PARAMETER					
C <sub>pd</sub>	Power dissipation capacitance (see Note 5)	47	pF			

NOTE 5:  $C_{pd}$  is used to determine the dynamic power consumption (P<sub>D</sub>), per package.  $P_D = (C_{PD} \times V_{CC}^2 \times f_I) + \Sigma (C_L \times V_{CC}^2 \times f_O)$ 

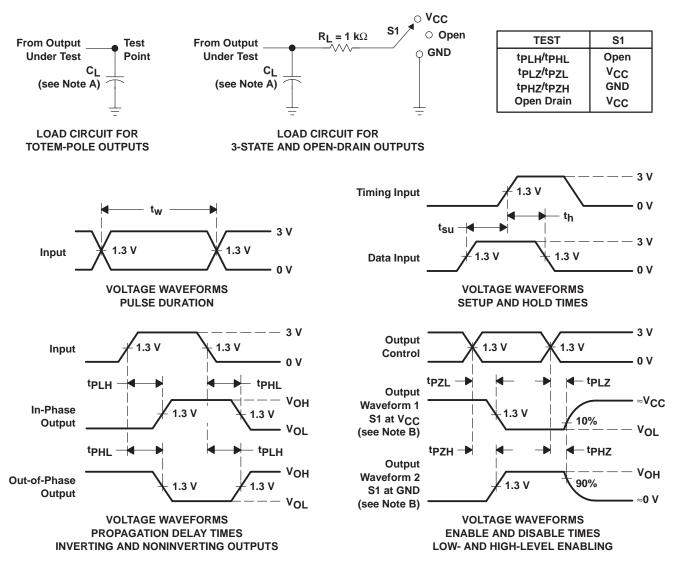
f<sub>I</sub> = input frequency

f<sub>O</sub> = output frequency

C<sub>L</sub> = output load capacitance

V<sub>CC</sub> = supply voltage

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>I</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \Omega$ ,  $t_f \leq 6$  ns.
- D. The outputs are measured one at a time, with one input transition per measurement.
- E. All parameters and waveforms are not applicable to all devices.
- F. tpLH and tpHL are the same as tpd.
- G. tpLz and tpHz are the same as tdis.
- H. tpzH and tpzL are the same as ten.

Figure 1. Load Circuit and Voltage Waveforms



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#### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/	MSL rating/	Op temp (°C)	Part marking
	(1)	(2)			(3)	Ball material	Peak reflow		(6)
						(4)	(5)		
CD74HCT574QM96EP	Active	Production	SOIC (DW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HCT574EP
CD74HCT574QM96EP.A	Active	Production	SOIC (DW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HCT574EP
CD74HCT574QPWREP	Active	Production	TSSOP (PW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HCT574EP
CD74HCT574QPWREP.A	Active	Production	TSSOP (PW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HCT574EP
V62/04739-01XE	Active	Production	SOIC (DW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HCT574EP
V62/04739-01YE	Active	Production	TSSOP (PW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HCT574EP

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

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#### OTHER QUALIFIED VERSIONS OF CD74HCT574-EP:

Automotive : CD74HCT574-Q1

Military : CD54HCT574

#### NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Automotive Q100 devices qualified for high-reliability automotive applications targeting zero defects
- Military QML certified for Military and Defense Applications



SMALL OUTLINE PACKAGE



#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SOIC



#### NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

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SOIC



NOTES: (continued)

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- 9. Board assembly site may have different recommendations for stencil design.



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